- *EPIC*TM (Enhanced-Performance Implanted CMOS) Process
- Operating Range 2-V to 5.5-V V_{CC}
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), Thin Very Small-Outline (DGV), Thin Shrink Small-Outline (PW), and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) DIPs

description

These octal buffers/drivers are designed specifically to improve the performance and density of 3-state memory-address drivers, clock drivers, and bus-oriented receivers and transmitters.

The 'AHC240 devices are organized as two 4-bit buffers/line drivers with separate output-enable (\overline{OE}) inputs. When \overline{OE} is low, the device passes data from the A inputs to the Y outputs. When \overline{OE} is high, the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN54AHC240 is characterized for operation over the full military temperature range of -55° C to 125°C. The SN74AHC240 is characterized for operation from -40° C to 85°C.

FUNCTION TABLE (each 4-bit buffer/driver)

	ITS	OUTPUT
ŌE	A	Y
L	Н	L
L	L	н
н	Х	Z



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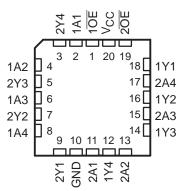
PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



SN54AHC240 J OR W PACKAGE
SN74AHC240 DB, DGV, DW, N, OR PW PACKAGE
(TOP VIEW)

	(,	
1OE [1A1 [2Y4 [1A2 [2Y3 [1A3 [2Y2 [1A4 [2Y1 [5 6	18 17 16 15 14 13	V <u>CC</u> 2OE 1Y1 2A4 1Y2 2A3 1Y3 2A2 1Y4
2Y1 [GND [9 10	12 11	1Y4 2A1
	L		

SN54AHC240 . . . FK PACKAGE (TOP VIEW)

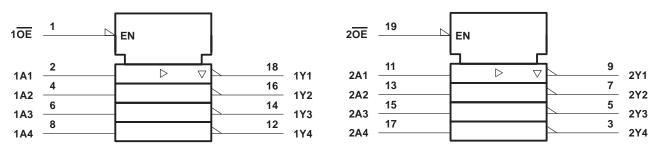


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SN54AHC240, SN74AHC240 OCTAL BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

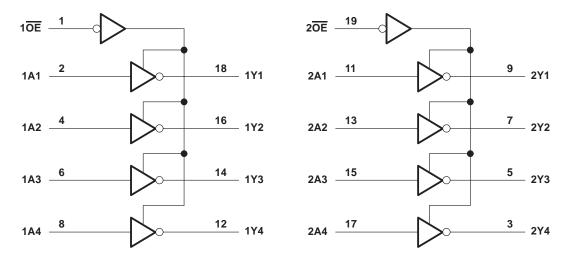
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logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[‡]

Input voltage range, V _I (see Note 1) Output voltage range, V _O (see Note 1) Input clamp current, I _{IK} (V _I < 0) Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC}) Continuous output current, I _O (V _O = 0 to V _{CC}) Continuous current through V _{CC} or GND Package thermal impedance, θ_{JA} (see Note 2): DB DG DW	-0.5 V to 7 V -0.5 V to 7 V -0.5 V to 7 V -0.5 V to V _{CC} + 0.5 V -20 mA ±20 mA ±25 mA ±75 mA package 70°C/W V package 92°C/W / package 58°C/W
	package
· · · · ·	/ package
Storage temperature range, T _{stg}	–65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51.



SCLS251F - OCTOBER 1995 - REVISED JANUARY 2000

recommended operating conditions (see Note 3)

			SN54A	SN54AHC240		N54AHC240 SN74AHC240			LINUT
			MIN	MAX	MIN MAX		UNIT		
Vcc	Supply voltage		2	5.5	2	5.5	V		
		V _{CC} = 2 V	1.5		1.5				
VIH	High-level input voltage	$V_{CC} = 3 V$	2.1		2.1		V		
		V _{CC} = 5.5 V	3.85		3.85				
		$V_{CC} = 2 V$		0.5		0.5			
VIL	Low-level input voltage	$V_{CC} = 3 V$		0.9		0.9	V		
		V _{CC} = 5.5 V		1.65		1.65	1		
VI	Input voltage	-	0	5.5	0	5.5	V		
Vo	Output voltage		0	VCC	0	VCC	V		
	High-level output current	$V_{CC} = 2 V$		-50		-50	μA		
ЮН		V_{CC} = 3.3 V ± 0.3 V		-4		-4			
		$V_{CC} = 5 V \pm 0.5 V$		-8		-8	mA		
		$V_{CC} = 2 V$		50		50	μΑ		
IOL	Low-level output current	V_{CC} = 3.3 V ± 0.3 V		4		4	mA		
		$V_{CC} = 5 V \pm 0.5 V$		8		8	mA		
A # / A	Input transition rise or fell rate	V_{CC} = 3.3 V ± 0.3 V		100		100	200		
$\Delta t / \Delta v$	Input transition rise or fall rate $V_{CC} = 5 V \pm 0$			20		20	ns/V		
TA	Operating free-air temperature		-55	125	-40	85	°C		

NOTE 3: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	Vaa	Т	₄ = 25°C	;	SN54A	HC240	SN74AHC240		UNIT
PARAMETER	TEST CONDITIONS	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
		2 V	1.9	2		1.9		1.9		
	I _{OH} = -50 μA	3 V	2.9	3		2.9		2.9		
∨он		4.5 V	4.4	4.5		4.4		4.4		V
	$I_{OH} = -4 \text{ mA}$	3 V	2.58			2.48		2.48		
	I _{OH} = -8 mA	4.5 V	3.94			3.8		3.8		
		2 V			0.1		0.1		0.1	
	I _{OL} = 50 μA	3 V			0.1		0.1		0.1	
VOL		4.5 V			0.1		0.1		0.1	V
	I _{OL} = 4 mA	3 V			0.36		0.5		0.44	
	I _{OL} = 8 mA	4.5 V			0.36		0.5		0.44	
lj	$V_I = V_{CC}$ or GND	0 V to 5.5 V			±0.1		±1*		±1	μA
loz†	$V_{O} = V_{CC}$ or GND, VI (OE) = VIL or VIH	5.5 V			±0.25		±2.5		±2.5	μΑ
ICC	$V_{I} = V_{CC} \text{ or GND}, \qquad I_{O} = 0$	5.5 V			4		40		40	μΑ
Ci	$V_I = V_{CC}$ or GND	5 V		2.5	10				10	pF
Co	$V_{O} = V_{CC} \text{ or } GND$	5 V		3.5						pF

* On products compliant to MIL-PRF-38535, this parameter is not production tested at $V_{CC} = 0 V$.

[†] The parameter I_{OZ} includes the input leakage current.



SN54AHC240, SN74AHC240 **OCTAL BUFFERS/DRIVERS** WITH 3-STATE OUTPUTS

SCLS251F - OCTOBER 1995 - REVISED JANUARY 2000

switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

00	•		, (-	-						
DADAMETED	FROM	то	LOAD	Τ ₄	λ = 25°C	;	SN54A	HC240	SN74A	HC240	UNIT
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MIN MAX	
^t PLH		Y	Ci = 15 pE		5.3*	7.5*	1*	9*	1	9	20
^t PHL	A	T	C _L = 15 pF		5.3*	7.5*	1*	9*	1	9	ns
^t PZH	OE	Y	C _L = 15 pF		6.6*	10.6*	1*	12.5*	1	12.5	ns
^t PZL	OE	T	CL = 15 pr		6.6*	10.6*	1*	12.5*	1	12.5	115
^t PHZ	OE	Y	C _L = 15 pF		7.8*	11.5*	1*	12.5*	1	12.5	ns
^t PLZ	OE	T	CL = 15 pr		7.8*	11.5*	1*	12.5*	1	12.5	115
^t PLH	А	Y	C _I = 50 pF		7.8	11	1	12.5	1	12.5	ns
^t PHL			CL = 30 pr		7.8	11	1	12.5	1	12.5	115
^t PZH	OE	Y	C _L = 50 pF		9.1	14.1	1	16	1	16	ns
^t PZL	UE UE		CL = 30 pr		9.1	14.1	1	16	1	16	115
^t PHZ	OE	Y	C _I = 50 pF		10.3	14	1	16	1	16	ns
^t PLZ			0L = 30 pr		10.3	14	1	16	1	16	115
^t sk(o)			C _L = 50 pF			1.5**				1.5	ns

* On products compliant to MIL-PRF-38535, this parameter is not production tested.

** On products compliant to MIL-PRF-38535, this parameter does not apply.

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

DADAMETED	FROM	TO LOAD		O LOAD $T_A = 25^{\circ}C$;	SN54A	HC240	SN74A	UNIT	
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
^t PLH	А	Y	C _I = 15 pF		3.6*	5.5*	1*	6.5*	1	6.5	ns
^t PHL		г	CL = 15 pr		3.6*	5.5*	1*	6.5*	1	6.5	115
^t PZH	OE	Y	Y CI = 15 pF		4.7*	7.3*	1*	8.5*	1	8.5	ns
^t PZL	UE	ř	CL = 15 pr		4.7*	7.3*	1*	8.5*	1	8.5	115
^t PHZ	OE	Y	C _L = 15 pF		5.2*	7.2*	1*	8.5*	1	8.5	ns
^t PLZ	OE	I	CL = 15 pr		5.2*	7.2*	1*	8.5*	1	8.5	115
^t PLH	А	Y	C _I = 50 pF		5.1	7.5	1	8.5	1	8.5	ns
^t PHL		I	CL = 30 pr		5.1	7.5	1	8.5	1	8.5	115
^t PZH	OE	Y	C _L = 50 pF		6.2	9.3	1	10.5	1	10.5	ns
^t PZL		I	CL = 30 pr		6.2	9.3	1	10.5	1	10.5	115
^t PHZ	OE	OF Y	C _I = 50 pF		6.7	9.2	1	10.5	1	10.5	200
^t PLZ	OE	T	0L = 30 pr		6.7	9.2	1	10.5	1	10.5	ns
^t sk(o)			C _L = 50 pF			1**				1	ns

* On products compliant to MIL-PRF-38535, this parameter is not production tested.

** On products compliant to MIL-PRF-38535, this parameter does not apply.



noise characteristics, V_{CC} = 5 V, C_L = 50 pF, T_A = 25^{\circ}C (see Note 4)

	PARAMETER				UNIT
	FARAMETER	MIN TYP MAX		UNIT	
V _{OL(P)}	Quiet output, maximum dynamic V _{OL}		0.6		V
VOL(V)	Quiet output, minimum dynamic V _{OL}		-0.6		V
VOH(V)	Quiet output, minimum dynamic V _{OH}		4.6		V
VIH(D)	High-level dynamic input voltage	3.5			V
V _{IL(D)}	Low-level dynamic input voltage			1.5	V

NOTE 4: Characteristics are for surface-mount packages only.

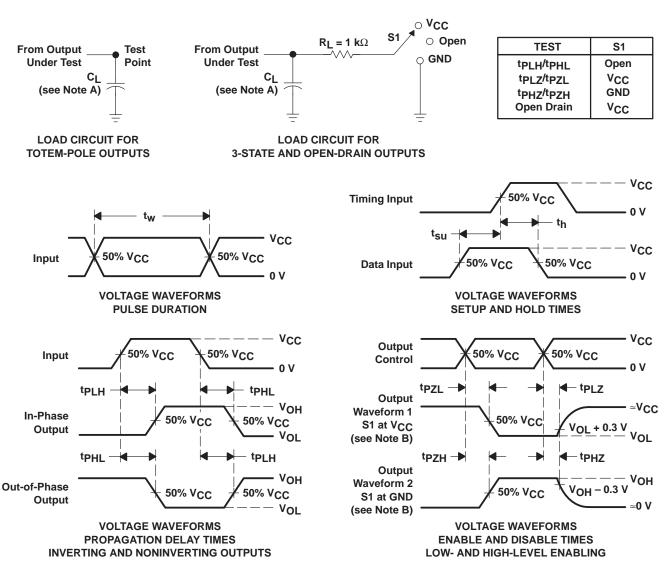
operating characteristics, V_{CC} = 5 V, T_A = 25° C

	PARAMETER	TEST CO	ONDITIONS	TYP	UNIT
Cpd	Power dissipation capacitance	No load,	f = 1 MHz	10	pF



SN54AHC240, SN74AHC240 **OCTAL BUFFERS/DRIVERS** WITH 3-STATE OUTPUTS

SCLS251F - OCTOBER 1995 - REVISED JANUARY 2000



PARAMETER MEASUREMENT INFORMATION

NOTES: A. CL includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_Q = 50 Ω , t_f \leq 3 ns, t_f \leq 3 ns.

D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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